## Applicant(s)/Patent Under Reexamination Application/Control No. 10/637,716 KERNER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2837 Patrick Miller

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
;	Α	US-6,611,125	08-2003	Nagata et al.	318/727
	В	US-5,175,483	12-1992	Fujii et al.	318/807
	С	US-6,144,181	11-2000	Rehm et al.	318/629
	D	US-4,649,328	03-1987	Leonard et al.	318/271
	Ε	US-5,477,114	12-1995	Yamada et al.	318/457
	F	US-			
	G	US-			
·	Н	US-			
	ı	US-			
	J	US-			
:	к	US-			
	L	US-			
	M	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
F	: N	JP 2001169584 A	06-2001	Japan	IGARASHI et al.	H02P 05/17
	, 0	JP 08140386 A	05-1996	Japan	IWASHITA et al.	H02P 05/00
	P	JP 2003210888 A	07-2003	Japan	KOMORI, TAKASHI	D06F 33/02
	į Q	EP 1088674 A1	04-2001	European Patent	IGARASHI et al.	B41J 19/20
	R					
	s					
	. Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	· V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.